

FQP19N20 200V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply, DC-AC converters for uninterrupted power supply, motor control.

Features

- + 19.4A, 200V, $R_{DS(on)}$ = 0.15 Ω @V_{GS} = 10 V + Low gate charge (typical 31 nC)
- Low Crss (typical 30 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP19N20	Units
V _{DSS}	Drain-Source Voltage		200	V
I _D	Drain Current - Continuous (T _C = 25°C)		19.4	А
	- Continuous (T _C = 100°C)		12.3	А
I _{DM}	Drain Current - Pulsed	(Note 1)	78	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	250	mJ
I _{AR}	Avalanche Current	(Note 1)	19.4	A
E _{AR}	Repetitive Avalanche Energy	(Note 1)	14	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
PD	Power Dissipation (T _C = 25°C)		140	W
	- Derate above 25°C		1.12	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purposes,		300	°C
	1/8" from case for 5 seconds		000	Ŭ

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction-to-Case		0.89	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient		62.5	°C/W
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April 2000

ТМ

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	200			V
ΔΒV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu A$, Referenced to $25^{\circ}C$		0.18		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V			1	μA
		V _{DS} = 160 V, T _C = 125°C			10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	rootoriotioo					
	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 9.7 \text{ A}$		0.12	0.15	Ω
9 _{ES}	Forward Transconductance	V _{DS} = 40 V, I _D = 9.7 A (Note 4)		14.5		S
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		1220	1600	pF
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		1220	1600	pF
	Devenue Transfer Connectioner	f = 1.0 MHz		220	290	рг
Switchi	ng Characteristics					P.
t _{d(on)}	Turn-On Delay Time			20	50	ns
t _r	Turn-On Rise Time	$V_{DD} = 100 \text{ V}, \text{ I}_{D} = 19.4 \text{ A},$		190	390	ns
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 25 \Omega$		55	120	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		80	170	ns
Q _n	Total Gate Charge	$V_{\rm PO} = 160 \text{V}$ Ip = 19.4 A		31	40	nC
Q _{as}	Gate-Source Charge	$V_{DS} = 10 V$		8.6		nC
Q _{ad}	Gate-Drain Charge	(Note 4, 5)		13.5		nC
J-			1	1	1	<u> </u>
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				-
I _S	Maximum Continuous Drain-Source Diode Forward Current				19.4	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				78	A
Ven	Drain-Source Diode Forward Voltage	$V_{CS} = 0 V_{.} I_{S} = 19.4 A$			15	V

 $V_{GS} = 0 V, I_{S} = 19.4 A,$

 dI_F / dt = 100 A/µs

(Note 4)

140

0.69

ns

μC

Q _{rr}	
Notos	

t_{rr}

Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.0mH, I_{AS} = 19.4A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. $I_{SD} \le 19.4A$, di/dt $\le 300A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C 4. Pulse Test : Pulse width $\le 300\mu s$, Duty cycle $\le 2\%$ 5. Essentially independent of operating temperature

Reverse Recovery Time

Reverse Recovery Charge

Rev. A, April 2000

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Rev. A, April 2000



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